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| <b>Notice of References Cited</b> | Application/Control No.<br>10/535,388 | Applicant(s)/Patent Under<br>Reexamination<br>KUSUNOKI ET AL. |             |
|                                   | Examiner<br>Aaron Williams            | Art Unit<br>4135  | Page 1 of 1 |

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|   | M | US-  |                 |            |                |

**FOREIGN PATENT DOCUMENTS**

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